Form PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. PATENT AND TRADEMARK OFFICE MI22-1330 09/653,149 LIST OF CONDENSES BY APPLICANT Garo J. Derderian (Use several sheets if necessary) APPLICANT GROUP FILING DATE August 31, 2000 2818 U.S. PATENT DOCUMENTS Subclass Date Class Filing Date Document Name *Examiner If Appropriate 6,482,740 11/2002 Soininen et al ΑB 5,908,947 06/1999 Vaartstra 2002/0142488 10/2002 Hong, Suk-Kyoung ΑD 6,403,156 06/2002 Jang ΑE 6,746,930 06/2004 Yang 2005/0018381 1/2005 McClure AG ΑI ΑJ ΑK FOREIGN PATENT DOCUMENTS Class Subclass Translation Document Date Country Number AΙ AM OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) ΑO Ritala et al, "Perfectly Conformal TiN and Al203 Films Deposited by Atomic Layer Deposition," Chemical Vapor Deposition, v. 5, No. 1, 1999, pp. 7-9. ΑP Suntola, "Surface Chemistry of Materials Deposition at Atomic Layer Level," Applied Surface Science, vol. 100/101, March 1996, pp. 391-398 T. Suntola, Atomic Layer Epitaxy, Handbook of Crystal Growth, Vol. 3, 1994, pp. 603-Leskela and Ritala, ALD Precursor Chemistry: Evolution and Future Challenges, J. Phys. IV France 9 (1999), pages 837-852. DATE CONSIDERED EXAMINER 5/3/06 *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

١ الم		MAR 1 1 2	1005 16						
Form PTO-14	149	A RAIL	a*./	EPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. MI22-1330 09/653,149					
		LIST OF APPLEAD	BY APPLIC ets if necessary)	CANT	APPLICANT	Garo J	I. Derderia	រោ	
					FILING DATE August 31, 200		GRC 2818		
				U.S. PATENT DOCUMENTS	-				
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing If Appr	Date opriate
T	AA	09/653,156		Agarwal (as amended 10 3/2004, and 12/2004))/2003,				
	AB								
	AC								
	AD								
	AE								
	AF.								
	AG								
	AH								
	.AI								
	AJ							<u>.</u>	
	AK							·	
	·	r		FOREIGN PATENT DOCUMEN	rrs			 	
		Document Number	Date	Country	i	Class	Subclass	Trans	lation
	 							Yes	No
	AL		+	· · · · · · · · · · · · · · · · · · ·			 		
	AM		+	 			 		
	AN	07	THER REFEREN	NCES (including Author, Title, Date	e, Pertinent Pages, Etc.				<u> </u>
	АО			\					
	AP			$\overline{}$					
	AQ								
EXAMINER		Charle		DATE CONSIDER	red 5/3/0	o 6			
		if reference considered, w		itation is in conformance with MI	PEP 609; Draw line th	rough citat	ion if not in	conformance	and not

Sheet 1 of 1

Form PTO-	1449			MENT OF COMMERCE TRADEMARK OFFICE	ATTY. DOCKE MI22-1330	T NO.		SERIAL NO. 09/653,149				
		LIST OF ART CITED (Use several sheets		น	APPLICANT:	APPLICANT: Garo J. Derderian et al.						
					FILING DATE GROUP August 31, 2000 2818							
U.S. PATEN	U.S. PATENT DOCUMENTS											
Examinar's Initials		Document Number	Data	Name		Class	Subclas	s Filing	Dato oprlate			
7		2002/0153579 A1	10/2002	Yamarnoto								
	AB	2002/0182820 A1	12/2002	Choi et al.			<u>[</u>					
	AC	2002/0197744 A1	12/2002	Lee ·					.]			
	A0	2004/0018747 A1	01/2004	Lee et al.								
	AE	2004/0125541 A1	07/2004	Chung								
	AF	6,849,505 B2	02/2005	Lee et al.								
1/	AG	6,946,342 B2	09/2005	Yeo et al.								
V	М											
	٨											
FOREIGN F	ATEN	DOCUMENTS	· · · · · · · · · · · · · · · · · · ·									
		Document Number	Cate	Country		Cteas	Subclass		station No			
7	2	JP 2002/222934 A	08/2002	Japan								
	AK											
	AL											
OTHER RE	FEREN	CES (including Author,	Title, Date, Pe	ertinent Pages, Etc.)								
	AM											
	w		· · · · · · · · · · · · · · · ·									
			,,,									
	A0		, , ,	. \	\							
				· · · · · · · · · · · · · · · · · · ·								
EXAMINER	J.	DATE CONSIDE	RED OS	103/06								
*EXAMINER: considered. In	initial if nclude o	reference considered, when opy of this form with next or	her or not citatio	n is in conformance with MF	EP 609; Draw line t	hrough cita	ition if not	in conformance	and not			

RECEIVED CENTRAL FAX CENTER 2003/004

DEC 1 6 2005

Sheet 1 of 2

Form	PTO-1	449				ENT OF COMMERCE TRADEMARK OFFICE	ATTY, DOCKE MI22-1330	T NO.		SERIAL NO. 09/653,149				
			LIST	OF ART CITED (Use several shoots		nt i	APPLICANT:	Garo J. C	erderlan et al.					
			,				FILING DATE August 31, 200	0		GROUP 2818				
U.S. P	ATEN	T DOC	UME	NTS				<u>.</u>						
Examin Initials	era			Document Number	Date	Name 1		Chass	Subcla	25	Filing I If Appro			
1		*	6,3	59, 2 95 B2	03/2002	Lee et al.								
		AB	6,5	96,602 B2	07/2003	Lizuka et al.								
		AC	6,6	27,462 B1	09/2003	Yang et al.								
		40	6,8	24,816	11/2004	Aaltonen et al.			`					
		AE	6,6	84,186 B1	12/2003	Callegari et al.								
		AP	6,30	07,730	10/2001	Yamanishi, Nobuyuki								
		AG	6,8	00,892	10/2004	Bhattacharyya, Arup								
		М	5,8	11,344	09/1998	Tu et al.								
		Ai	6,5	96,583	07/2003	Agarwal et al.								
		AJ	6,0	69,053	05/2000	Ping et al.								
		AK	6,0	33,987	03/2000	Li et al.								
V	′	AL	5,8	85,882	03/1999	Schugraf et al.								
FORE	IGN P	ATEN	DOC	UMENTS				r						
				Document Number	Cate	Country		Class	Subda	53 <u> </u>	Translation			
		м	_								Yes	No		
		AN	\vdash							十				
		A O	<u> </u>						<u> </u>	十				
OTHE	R REI	EREN	CES (including Author,	Title, Date, Pe	ertinent Pages, Etc.)		L						
		~												
		- A												
		AR												
EXAMI	AER UC	li		DATE CONSIDE	RED 05/	03/06								
"EXAM conside	INER: ared. lr	Initial if	opy of I	ice considered, whe his form with next o	ther or not citatic ornmunication to	an is in conformance with MF applicant.	EP 609; Draw line t	hrough cita	atlon if no	et in con	nformance	ton bns		

*** 4 *** 12/16/2005 16:51 FAX 5098383424

WELLS ST JOHN PS

Form PTO-1	449	U. P	S. DEPARTM ATENT AND 1	ENT OF COMMERCE TRADEMARK OFFICE	ATTY, DOCKE MI22-1330	T NO.		ROUP 118		
		LIST OF ART CITED I		т	APPLICANT:	Garo J. C	erderian e	t al.		
					FILING DATE August 31, 200	0	GR 281			
U.S. PATEN	n poc	UMENTS						· · · · · · · ·	·····	
"Examinar's Initials		Document Number	Oate	Name		Class	Subclass	Filing I II Appro	Date priate	
4	*	6,174,770	00/2001	Chi, Min-hwa	·					
7	AB	2005/0082593 A1	04/2005	Lee et al.						
TV	AC .	2003/0215960	11/2003	Mitsuhashi, Toshiro						
2	40	2002/0109198 A1	08/2002	Yang et al.			<u> </u>			
	Æ						<u> </u>	ļ		
	~						$\overline{}$			
	AG				_			}		
	AH							1		
	N					ļ	<u> </u>	 		
	۸.							ļ	\	
	**					<u> </u>		-		
	^4		l				<u> </u>	I		
FOREIGN F	ATENT	DOCUMENTS	Dete	Country	<u> </u>	Class	Subdess	Trans	station	
		Document Number		Country		U.S.S	Gubasss	Yes	No	
	AM							ļ		
	**					ļ	<u> </u>			
	۸٥		<u> </u>				<u> </u>	<u> </u>		
OTHER RE	FEREN	CES (Including Author,	Title, Date, Pe	ertinent Pages, Etc.)						
	AP									
	A Q									
	AR.									
EXAMINER UL	li	DATE CONSIDE	RED 05	5/03/06						
*EXAMINER: considered.	initial if include c	reference considered, whe opy of this form with need o	ther or not citati ommunication to	on is in conformance with M o applicant.	PEP 609; Oraw line	through cit	aton if not is	onformance	e and not	

Form PTO-14	49		•		EPARTMENT OF COMMERCE I AND TRADEMARK OFFICE	ATTY. DOCKET I	۲O.		SERIAL NO. 09/653,149				
/	51 P	•	OF ART CITED		CANT	APPLICANT G	uro J. Derde	rian					
JA	N 2 B	2004	o/	• •		FILING DATE August 31, 2000		GRO1 2812	UP				
THE STATE OF THE S		.6	§		U.S. PATENT DOCUMENTS								
*Examiner Initial	TRADE	Numb	nent er	Date	Name		Class	Subclass	Filing If Appro				
T	AA	6,162,	712	12/00	Baum								
7	АB	6,018,	065	01/00	Baum								
N	AC	6,281,	543	08/01	Al-Shareef et al								
	AD				<u></u>								
	AE												
	AF						ļ	·	·				
	AG						ļ						
	АH												
	AI			<u>.</u>									
	AJ												
	AK						<u> </u>						
		1 .			FOREIGN PATENT DOCUMEN	NTS	Γ	I	i _				
		Docu: Numb		Date	Country	Class	Subclass	Trans Yes	lation No				
	AL				·								
	AM												
	AN			<u> </u>			<u></u>	l	<u> </u>	L			
			от	HER REFERE	NCES (including Author, Title, Dat	e, Pertinent Pages, Etc	:.) 						
	AO												
	AP		_							_			
	AQ									 -			
						<u> </u>							
EXAMINER		Lhu	uli		DATE CONSIDE	5/	3/06		<u></u>				
•EXAMINEI	t: Initial	if refere	ence considered, wh	nether or not o	itation is in conformance with M	PEP 609; Draw line	through cits	tion if not in	conformance	e and not			
considered.	Include c	opy of the	his form with next	communication	to spplicant.								

Form PTO-14	2				EPARTMENT OF COMMERCE T AND TRADEMARK OFFICE	ATTY, DOCKET I		SERIAL NO. 09/653,149					
/o ' '		ZIST	OF ART CITED (Use several sheets		CANT	APPLICANT G	aro J. Derde	GROUP					
OCT O	o Zuva	SE 650)			_	FILING DATE August 31, 2000		GRO 2818					
Examiner Initial	ya.	<i>§</i>			U.S. PATENT DOCUMENTS								
Examiner Initial	DEM	Docu Numi	ment ber	Date	Name		Class	Subclass	Filing If Appr	Date opriate			
T	AA	5,452	.178	09/95	Emesh et al								
	ΑB	6,458	,416	10/02	Derderian et al								
	AC	6,309	,923	10/01	Tseng, Horng-Huei	EIVED							
	ΑD	6,548	,424	05/03	Putkonen OCT	18 2004							
	AE	6,632	,279	10/03	Ritala TECH CENTER 2800								
	АF	6,270	,572	08/01	Kim et al								
	AG	6,780	1,704	4/03	Sneh et al								
	АН	6,551	,399	08/04	Raaijmakers et al	·							
	AI												
	AJ						,						
	AK												
					FOREIGN PATENT DOCUMEN	TS	1		·				
		Docu Num'	iment ber	Date	Country	Class	Subclass	Tran:	No No				
	AL												
	AM												
	AN						L		L	<u></u>			
· · · · · · · · · · · · · · · · · · ·			ОП	IER REFERE	NCES (including Author, Title, Dat	e, Pertinent Pages, Etc	:-)	<u>-</u>					
	AO			_				-					
	ΑP												
									· 				
	AQ												
						•							
EXAMINER		nac	el .	_ , •	DATE CONSIDER	RED 5/3/	06						
*EXAMINER considered. I	Initial	if refere	ence considered, wh his form with next o	ether or not communication	itation is in conformance with Mit to applicant.	PEP 609; Draw line t	hrough citat	ion if not in	conformance	and not			